	Hits	Search Text	DBs	Time Stamp
1	7	("5870201" "5635336" "5770338" "5578423").pn.	IB: D() • . I D() •	2005/09/28 17:24
2	2202	precision with register	IH: D( ) • . I D( ) •	2005/09/28 17:29
3	73	precision with register and resist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:29
4	44	precision with register and resist and exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:29
5	1 ″	precision with register and resist and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:36
6	4	precision with register and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:31
7	1436	resist and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:30
8	388	register and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:31
9	68	register and resist and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:31

	Hits	Search Text	DBs	Time Stamp
10	553	(overlay overlap) and resist and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:32
11	28	(overlay overlap) and resist and first adj exposure and second adj exposure and register	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:32
12	24	(overlay overlap) and resist and first adj exposure and second adj exposure and register and (measure measuring measured)	EPO; JPO;	2005/09/28 17:33
13	3	precision same register and resist and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:39
14	6308	(measure measuring measured) same (pattern patterns) and lithography	(H: P() + 11 P() +	2005/09/28 17:40
15	2119	(measure measuring measured) same (pattern patterns) and lithography and integrated adj circuit	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:40
16	97	(measure measuring measured) same (pattern patterns) same displacement and lithography and integrated adj circuit	HEPO LIPO	2005/09/28 17:40
17	88	(measure measuring measured) same (pattern patterns) same displacement and lithography and integrated adj circuit and exposure	IH: D() • . 1 D() •	2005/09/28 17:45
18		(measure measuring measured) same (pattern patterns) same displacement and lithography and integrated adj circuit and exposure and register	IR: P() • 11P() •	2005/09/28 17:41

	Hits	Search Text	DBs	Time Stamp
19	67	(measure measuring measured) same (pattern patterns) same displacement and lithography and integrated adj circuit and exposure and resist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:41
20	35	(measure measuring measured) same (pattern patterns) same displacement and lithography and integrated adj circuit and exposure and resist and mark	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:41
21	13	(measure measuring measured) same (pattern patterns) same displacement and lithography and integrated adj circuit and first adj exposure and second adj exposure	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 17:46
22	2	"6368980".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 18:01
23	1	("5952247").PN.	US-PGPUB; USPAT; USOCR	2005/09/28 18:02
24	4	("6368980").URPN.	USPAT	2005/09/28 18:02
25	4	("6601314" "6440262").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 18:03
26	5	("6559063" "6589385" "6562188").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/28 18:03
27	368	438/5.ccls.	IB.PO TPO	2005/09/29 13:21

	Hits	Search Text	DBs	Time Stamp
28	1056	438/16.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/29 13:21
29	171	438/765.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/29 13:21
30	891	438/795.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/29 13:21
31	1819	430/22.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/29 13:21
32	2235	430/30.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/29 13:22
33	3363	430/311.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/29 13:22
34	1317	356/400.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/09/29